THE NEW LEVEL OF COATING THICKNESS MEASUREMENT AND MATERIAL ANALYSIS

Do you want maximum efficiency in your quality control? Do you have to measure coating thicknesses and material compositions highly precise? Our new FISCHERSCOPE® XDV® with XRF technology and the cutting-edge FISIQ® X software is your solution!

Super-fast sample positioning. High-speed Z-axis 6 x faster*

Rapid sample capture. Autofocus in under 2 seconds – 14 x faster*

Automated operation. Automated or manual hood for maximum flexibility

Unparalleled high precision and repeatable results. Optimized measurement geometry

Optimum sample illumination and picture capture. 10 x higher* camera resolution and multizone LED lighting

Device status always visible. Intuitive 180° status light

Enhanced usability and user guidance. New FISIQ® X software

*In comparison to FISCHERSCOPE® X-RAY XDV®-SDD.

Designed for an exceptionally wide range of applications

High-end XRF instrument for measuring thin and very thin layers, including < 0.05 µm, in many different industries.

Semiconductors
Measure ultrathin layers/ metallization on wafers for development and process control.

Energy & automotive
Optimized measurements for fuel cell and battery materials.

Banking, customs & jewelry
Accurate analysis of precious metals, coins and jewelry.

Defence
Measurements of special coating systems and high reliability electronics.

And many more...

Explore the new FISCHERSCOPE® XDV®!

glow-up.helmut-fischer.com

- **Measure fast**
- **Measure precise**
- **Measure efficient**

GET YOUR FREE DEMO NOW!

FISCHER – globally leading in highly precise XRF measuring technology.

Boost your productivity with simplified and efficient workflows

FISIQ® X – THE FIRST XRF SOFTWARE WITH AI TECHNOLOGY

With our FISCHERSCOPE® XDV® and FISIQ® X software, you measure coating thickness up to 6 x faster and analyze materials up to 13 x faster** – thanks to improved algorithms and AI-supported spectrum analysis. Measure smarter, faster, and more user-friendly now!

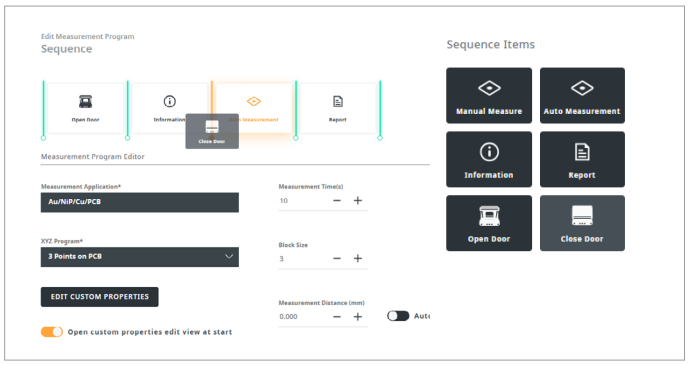
- **Simplified and modern user interface**
- **Guided and efficient workflows**
- **Various user roles**

*Comparison calculation time between WinFTM® 6 and FISIQ® X.

From inserting the sample to precise measuring results – in no time at all.

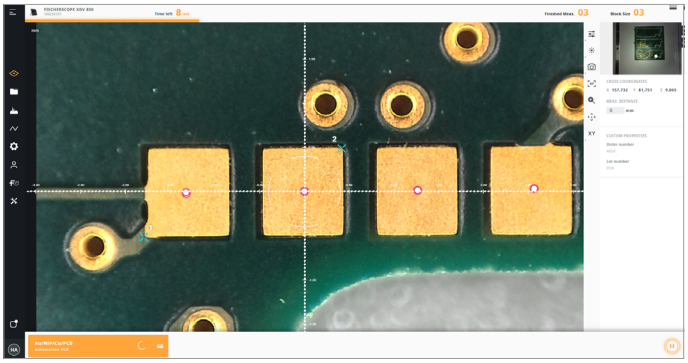
1. Calibrate quickly and easily.

Measure your standards with the simple and guided calibration workflow and benefit from the ready-to-use standard library.



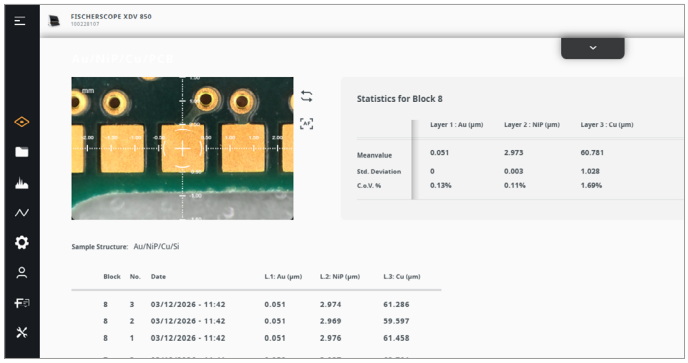
2. Build secure workflows.

Predefine your measuring program effortlessly with drag-and-drop to enhance your process safety and ensure consistent, repeatable results.



3. Measure with full control.

Place your sample and start the measuring program. See a live image and all relevant information clearly displayed for instant insights.



4. Obtain your results, ready to use.

Get instant element identification, view all results at a glance, and generate your report in just a few clicks.

Experience the new measuring solution now!
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